



## Absolute Maximum Ratings

Symbol	Parameter	Rating	Unit
<b>Common Ratings</b> ( $T_A = 25^\circ\text{C}$ Unless Otherwise Noted)			
$V_{DSS}$	Drain-Source Voltage	25	V
$V_{GSS}$	Gate-Source Voltage	$\pm 20$	
$T_J$	Maximum Junction Temperature	150	$^\circ\text{C}$
$T_{STG}$	Storage Temperature Range	-55 to 150	$^\circ\text{C}$
$I_S$	Diode Continuous Forward Current	$T_C=25^\circ\text{C}$ 40	A
<b>Mounted on Large Heat Sink</b>			
$I_{DP}$	300 $\mu\text{s}$ Pulse Drain Current Tested	$T_C=25^\circ\text{C}$ 150	A
		$T_C=100^\circ\text{C}$ 80	
$I_D$	Continuous Drain Current	$T_C=25^\circ\text{C}$ 60*	A
		$T_C=100^\circ\text{C}$ 50	
$P_D$	Maximum Power Dissipation	$T_C=25^\circ\text{C}$ 50	W
		$T_C=100^\circ\text{C}$ 20	
$R_{\theta JC}$	Thermal Resistance-Junction to Case	2.5	$^\circ\text{C}/\text{W}$
<b>Mounted on PCB of Minimum Footprint</b>			
$I_{DP}$	300 $\mu\text{s}$ Pulse Drain Current Tested	$T_A=25^\circ\text{C}$ 150	A
		$T_A=100^\circ\text{C}$ 80	
$I_D$	Continuous Drain Current	$T_A=25^\circ\text{C}$ 12	A
		$T_A=100^\circ\text{C}$ 5.5	
$P_D$	Maximum Power Dissipation	$T_A=25^\circ\text{C}$ 1.25	W
		$T_A=100^\circ\text{C}$ 0.25	
$R_{\theta JA}$	Thermal Resistance-Junction to Ambient	100	$^\circ\text{C}/\text{W}$

Note:

\* Current limited by bond wire.

## Electrical Characteristics ( $T_A = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Test Condition	APM2506NUB			Unit
			Min.	Typ.	Max.	
<b>Drain-Source Avalanche Ratings</b>						
$E_{AS}$	Drain-Source Avalanche Energy	$I_D=20\text{A}$ , $L=0.5\text{mH}$			100	mJ
<b>Static Characteristics</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$ , $I_{DS}=250\mu\text{A}$	25			V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=20\text{V}$ , $V_{GS}=0\text{V}$			1	$\mu\text{A}$
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$ , $I_{DS}=250\mu\text{A}$	1.3	1.8	2.5	V
$I_{GSS}$	Gate Leakage Current	$V_{GS}=\pm 20\text{V}$ , $V_{DS}=0\text{V}$			$\pm 100$	nA
$R_{DS(ON)}^a$	Drain-Source On-state Resistance	$V_{GS}=10\text{V}$ , $I_{DS}=40\text{A}$		4.8	6	m $\Omega$
		$V_{GS}=4.5\text{V}$ , $I_{DS}=20\text{A}$		7	9	
<b>Diode Characteristics</b>						
$V_{SD}^a$	Diode Forward Voltage	$I_{SD}=20\text{A}$ , $V_{GS}=0\text{V}$		0.7	1.1	V
$t_{rr}^b$	Reverse Recovery Time	$I_{SD}=10\text{A}$ , $dI_{SD}/dt = 100\text{A}/\mu\text{s}$		30		ns
$Q_{rr}^b$	Reverse Recovery Charge			14		nC
<b>Dynamic Characteristics<sup>b</sup></b>						
$R_G$	Gate Resistance	$V_{GS}=0\text{V}$ , $V_{DS}=0\text{V}$ , $F=1\text{MHz}$		1.0	2.1	$\Omega$
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}$ , $V_{DS}=15\text{V}$ , Frequency=1.0MHz		3100		pF
$C_{oss}$	Output Capacitance			680		
$C_{riss}$	Reverse Transfer Capacitance			520		
$t_{d(ON)}$	Turn-on Delay Time	$V_{DD}=15\text{V}$ , $R_L=15\Omega$ , $I_{DS}=1\text{A}$ , $V_{GEN}=10\text{V}$ , $R_G=6\Omega$		19		ns
$T_r$	Turn-on Rise Time			20		
$t_{d(OFF)}$	Turn-off Delay Time			62		
$T_f$	Turn-off Fall Time			43		
<b>Gate Charge Characteristics<sup>b</sup></b>						
$Q_g$	Total Gate Charge	$V_{DS}=15\text{V}$ , $V_{GS}=4.5\text{V}$ , $I_{DS}=40\text{A}$		37.5	56	nC
$Q_{gs}$	Gate-Source Charge			9.4		
$Q_{gd}$	Gate-Drain Charge			21		

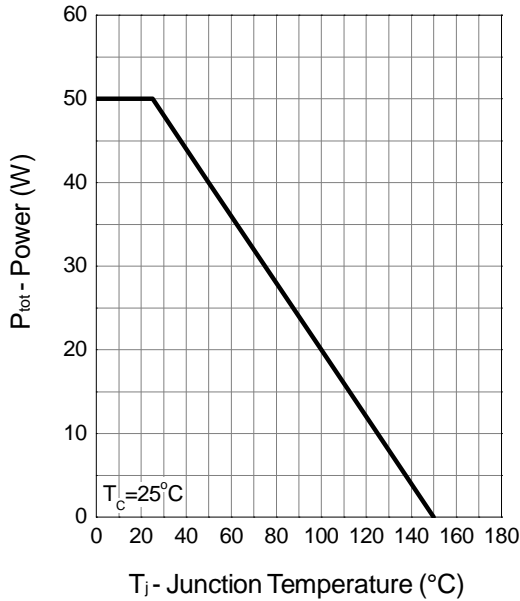
Notes:

a : Pulse test ; pulse width  $\leq 300\mu\text{s}$ , duty cycle  $\leq 2\%$ .

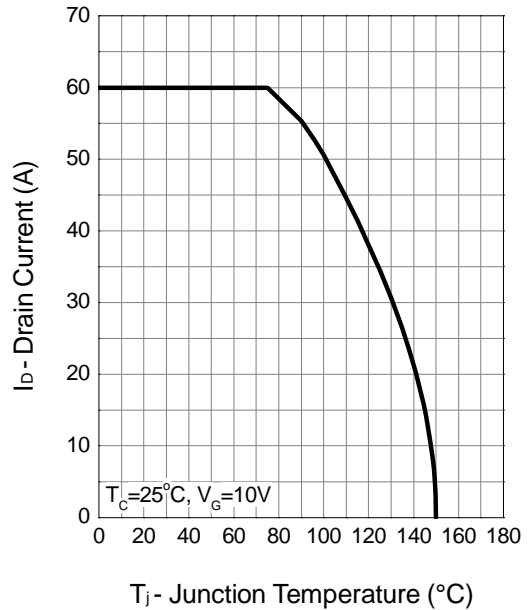
b : Guaranteed by design, not subject to production testing.

Typical Characteristics

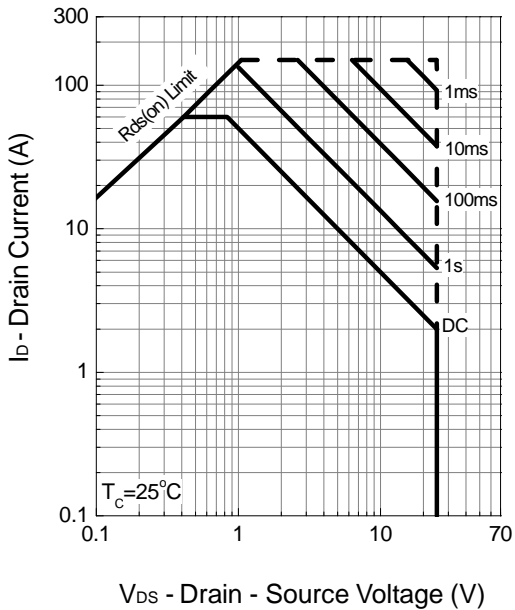
Power Dissipation



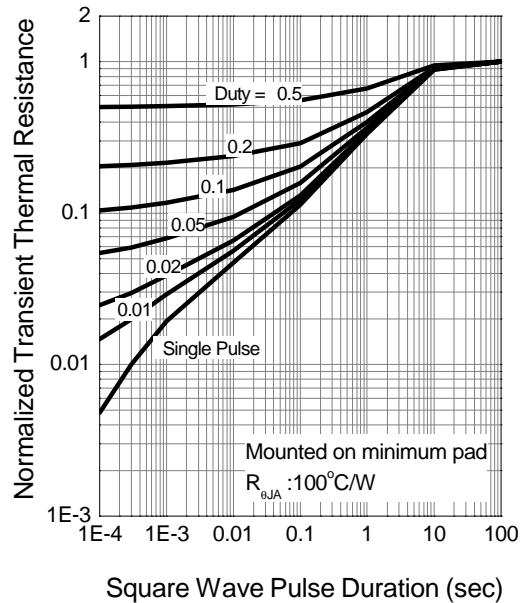
Drain Current



Safe Operation Area

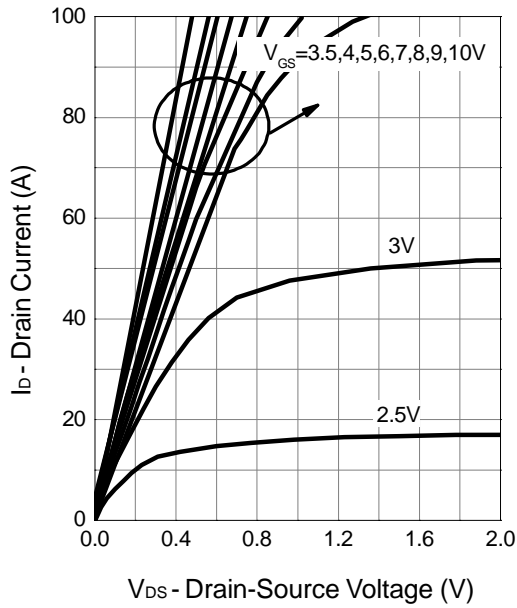


Thermal Transient Impedance

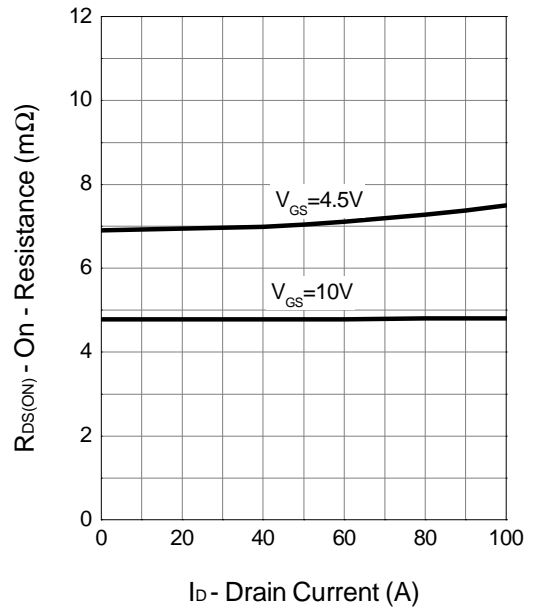


Typical Characteristics (Cont.)

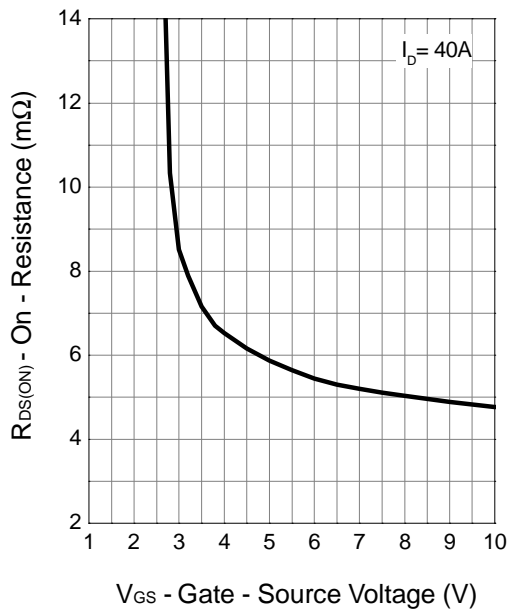
Output Characteristics



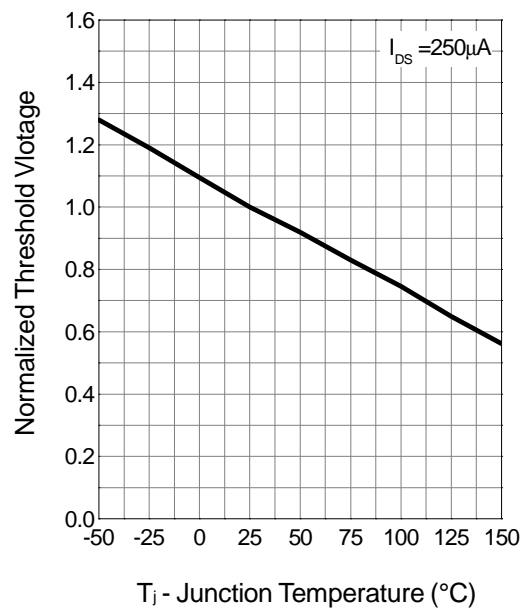
Drain-Source On Resistance



Drain-Source On Resistance

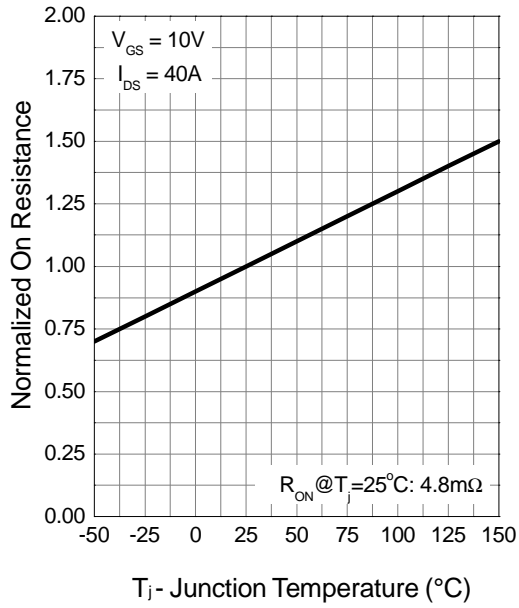


Gate Threshold Voltage

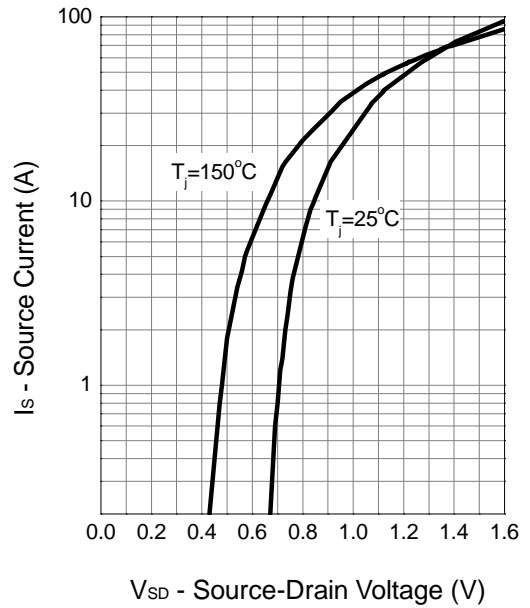


Typical Characteristics (Cont.)

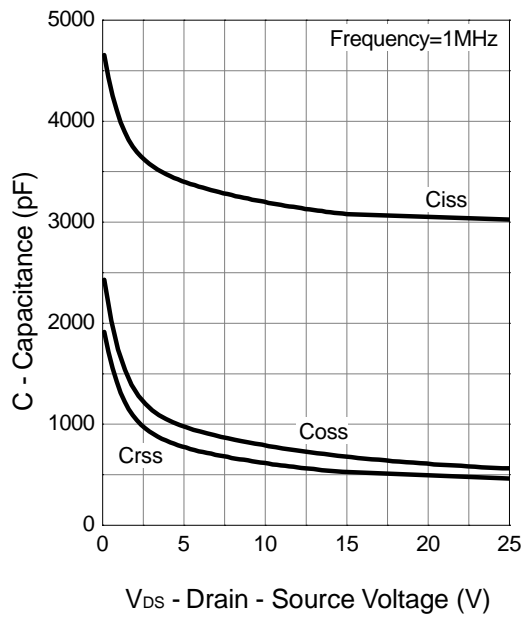
Drain-Source On Resistance



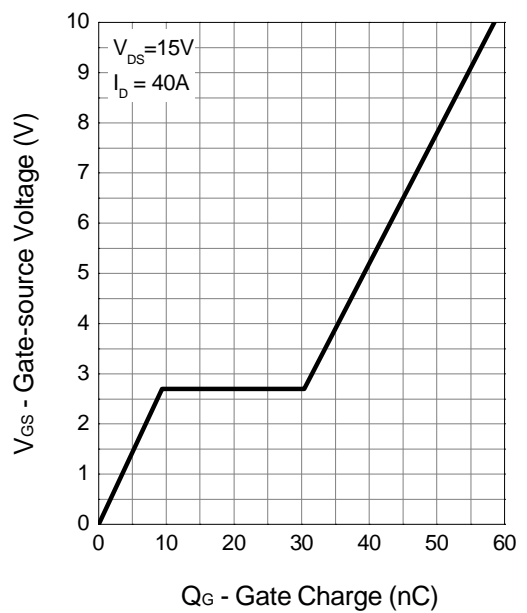
Source-Drain Diode Forward



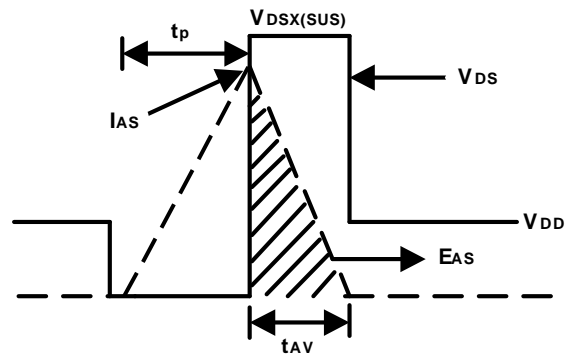
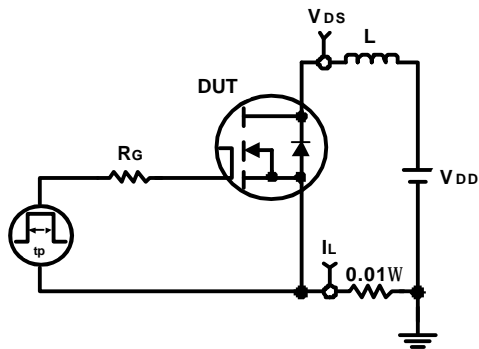
Capacitance



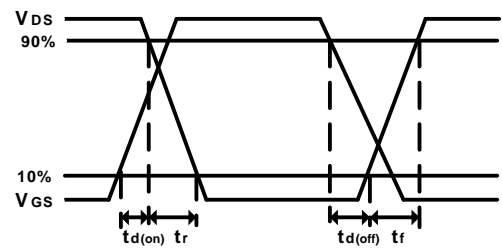
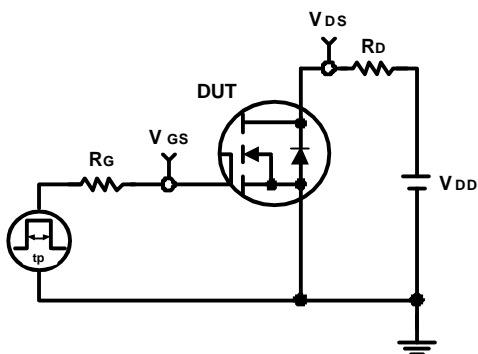
Gate Charge



## Avalanche Test Circuit and Waveforms

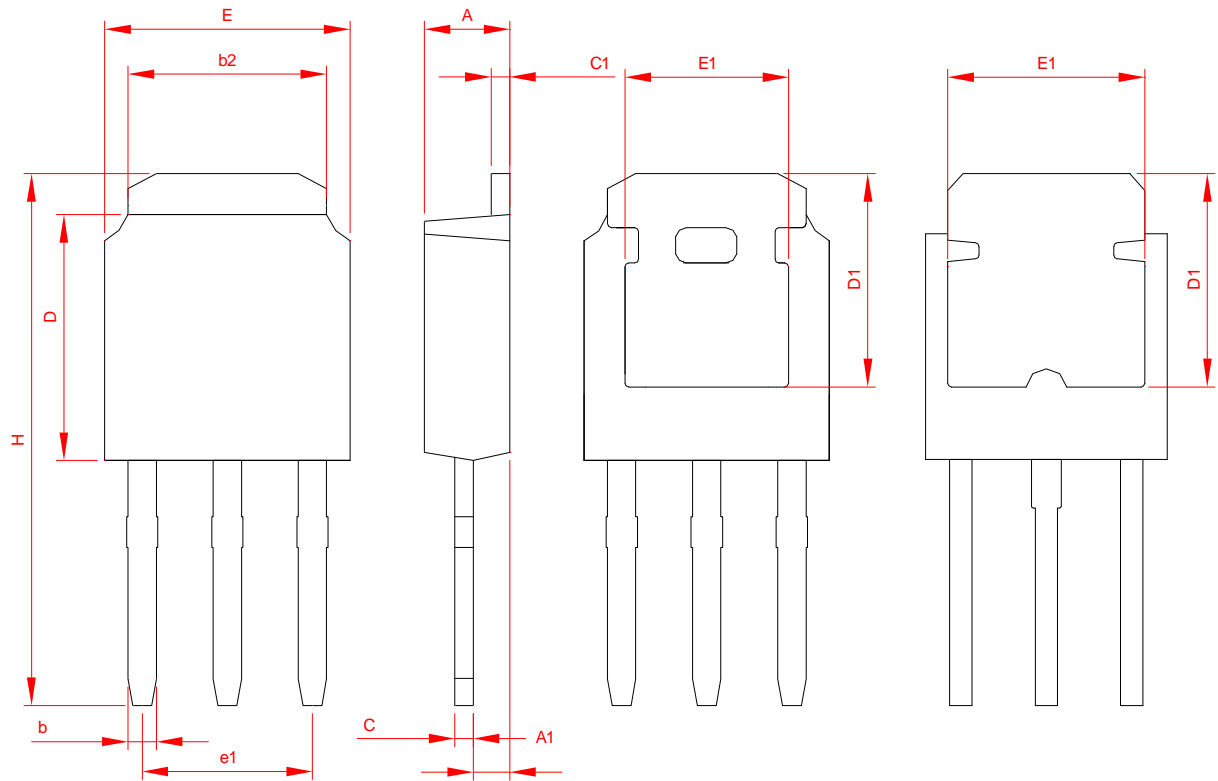


## Switching Time Test Circuit and Waveforms



Packaging Information

TO-251



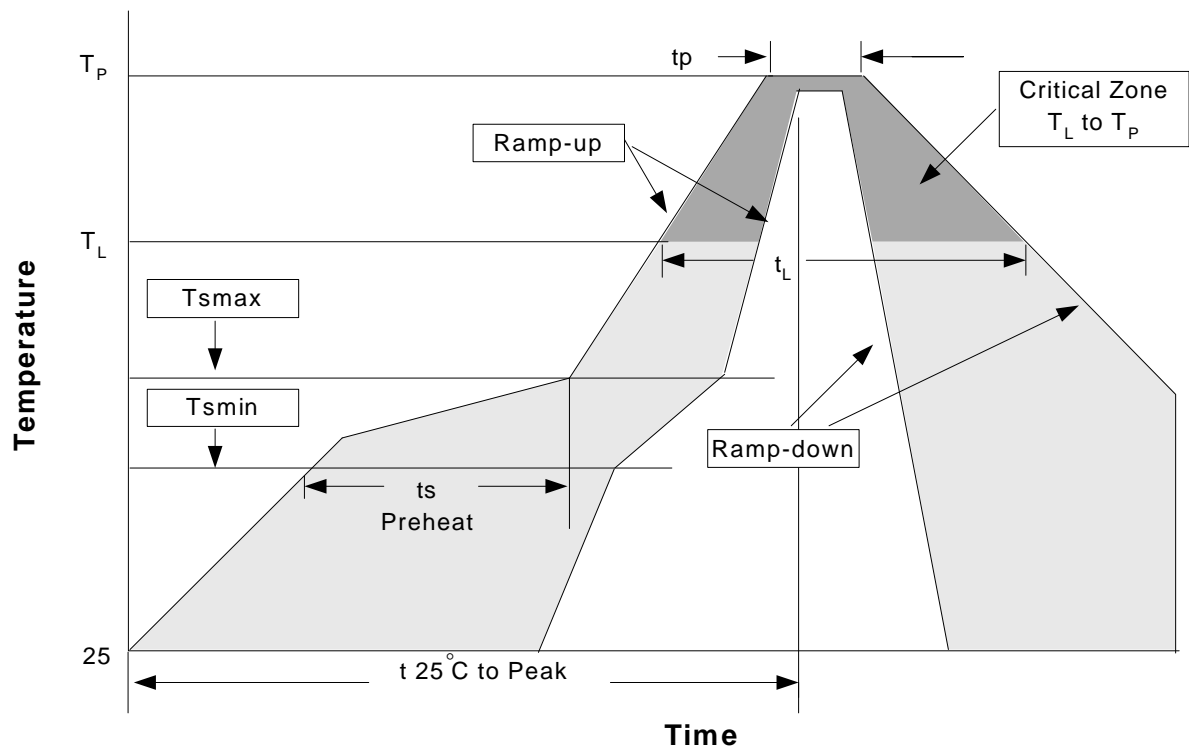
Dim	Millimeters		Inches	
	Min.	Max.	Min.	Max.
A	2.20	2.40	0.087	0.094
A1	1.02	1.27	0.040	0.050
b	0.50	0.88	0.020	0.035
b2	5.20	5.46	0.205	0.215
C	0.40	0.60	0.016	0.024
C1	0.40	0.60	0.016	0.024
D	5.40	6.20	0.213	0.244
D1	5.30	--	0.209	--
E	6.35	6.70	0.250	0.264
E1	4.40	5.40	0.173	0.213
e1	4.50	4.70	0.177	0.185
H	12.90	15.25	0.508	0.600



## Physical Specifications

Terminal Material	Solder-Plated Copper (Solder Material : 90/10 or 63/37 SnPb), 100%Sn
Lead Solderability	Meets EIA Specification RSI86-91, ANSI/J-STD-002 Category 3.

### Reflow Condition (IR/Convection or VPR Reflow)



### Classification Reflow Profiles

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
Average ramp-up rate ( $T_L$ to $T_P$ )	3°C/second max.	3°C/second max.
Preheat		
- Temperature Min ( $T_{smin}$ )	100°C	150°C
- Temperature Max ( $T_{smax}$ )	150°C	200°C
- Time (min to max) ( $t_s$ )	60-120 seconds	60-180 seconds
Time maintained above:		
- Temperature ( $T_L$ )	183°C	217°C
- Time ( $t_L$ )	60-150 seconds	60-150 seconds
Peak/Classification Temperature ( $T_p$ )	See table 1	See table 2
Time within 5°C of actual Peak Temperature ( $t_p$ )	10-30 seconds	20-40 seconds
Ramp-down Rate	6°C/second max.	6°C/second max.
Time 25°C to Peak Temperature	6 minutes max.	8 minutes max.

Notes: All temperatures refer to topside of the package .Measured on the body surface.

## Classification Reflow Profiles(Cont.)

Table 1. SnPb Eutectic Process – Package Peak Reflow Temperatures

Package Thickness	Volume mm <sup>3</sup> <350	Volume mm <sup>3</sup> ≥350
<2.5 mm	240 +0/-5°C	225 +0/-5°C
≥2.5 mm	225 +0/-5°C	225 +0/-5°C

Table 2. Pb-free Process – Package Classification Reflow Temperatures

Package Thickness	Volume mm <sup>3</sup> <350	Volume mm <sup>3</sup> 350-2000	Volume mm <sup>3</sup> >2000
<1.6 mm	260 +0°C*	260 +0°C*	260 +0°C*
1.6 mm – 2.5 mm	260 +0°C*	250 +0°C*	245 +0°C*
≥2.5 mm	250 +0°C*	245 +0°C*	245 +0°C*

\*Tolerance: The device manufacturer/supplier **shall** assure process compatibility up to and including the stated classification temperature (this means Peak reflow temperature +0°C. For example 260°C+0°C) at the rated MSL level.

## Reliability Test Program

Test item	Method	Description
SOLDERABILITY	MIL-STD-883D-2003	245°C,5 SEC
HOLT	MIL-STD 883D-1005.7	1000 Hrs Bias @ 125°C
PCT	JESD-22-B, A102	168 Hrs, 100% RH, 121°C
TST	MIL-STD 883D-1011.9	-65°C ~ 150°C, 200 Cycles

## Customer Service

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